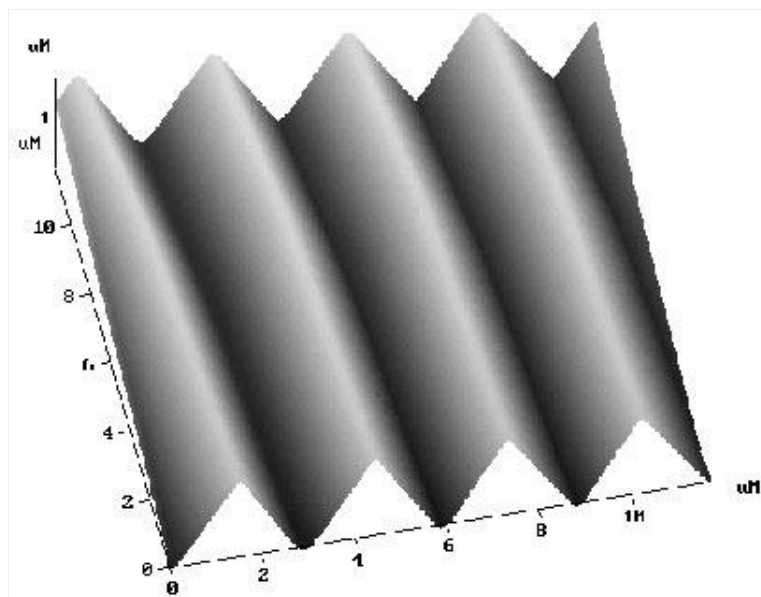
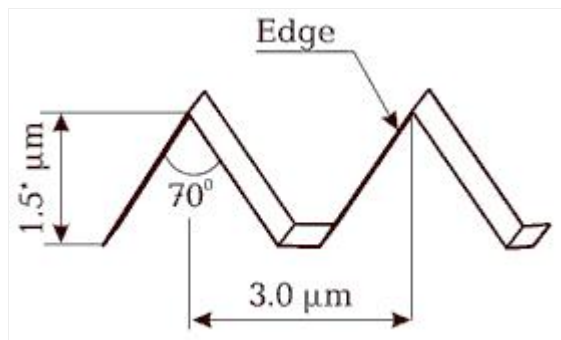


Product Description

Calibration grating TGG1 is intended for

- AFM calibration in X or Y axis;
- detection of lateral and vertical scanner nonlinearity;
- detection of angular distortion;
- tip characterization.



General Features

Structure	Si
Pattern type	1- D array of triangular steps (in X or Y direction) having precise linear and angular sizes
Period	3±0,05 μm
Chip size	5x5x0,5 mm
Effective area	central square 3x3 mm
Edge angle	70 degrees
Edge radius	≤10nm